


<b>Search Notes</b> 	<b>Application/Control No.</b> 10520795	<b>Applicant(s)/Patent Under Reexamination</b> CASTRO ET AL.
	<b>Examiner</b> Kim, Hee Soo	<b>Art Unit</b> 2157

SEARCHED			
Class	Subclass	Date	Examiner
709	201, 223	7/2/2008	HSK

SEARCH NOTES		
Search Notes	Date	Examiner
Updated East Search	7/2/2008	HSK

INTERFERENCE SEARCH			
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